

<b>Notice of References Cited</b>	Application/Control No. 10/564,894		Applicant(s)/Patent Under Reexamination MORIYA ET AL.	
	Examiner Hai H. Huynh		Art Unit 3747	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,840,218 B2	01-2005	Scholl et al.	123/435
*	B	US-7,146,964 B2	12-2006	Norimoto et al.	123/435
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2005-320872	11-2005	Japan	Nagai et al	F02D-41/40
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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